


Universidade de Aveiro 	<b>TEMA</b> Centre for Mechanical Technology and Automation
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### XPS\*


X-ray photoelectron spectroscopy

[http://nrd.web.ua.pt/?page\\_id=198](http://nrd.web.ua.pt/?page_id=198)

[tema.services@ua.pt](mailto:tema.services@ua.pt)

Applicant	
Name	
Status	<input type="checkbox"/> Undergraduate <input type="checkbox"/> Master <input type="checkbox"/> PhD <input type="checkbox"/> Researcher
Supervisor	
University / Department or Company address	
Phone	
email	

Sample Information	
Name of Sample	
Electrical conductivity	<input type="checkbox"/> Conductive <input type="checkbox"/> Non-conductive
form of sample (Powder / pellet / thin film...)	
Method of preparation (in brief)	
Composition / Impurities	
Special <i>ex-situ</i> sample handling instruction	
Special <i>in-situ</i> sample preparation (annealing / sputtering)	
High resolution scan elements (please specify the core level)	

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Literature Reference of a similar sample	Journal: Volume:      Year:      Page: Title:
Any specific feature expected	

### Any other sample detail or information

Particle size, substrate support, details of overlayer thickness and composition, light sensitive, magnetic sample, biohazard, carcinogen, Radioactive, Air reactive, water reactive, flammable, other, etc.

- The user agrees that all the provided information about the sample is complete and true.
- After XPS measurements the raw data will be provided in XY format.
- The sample should not contain any volatile/degassing materials which will affect Ultra High vacuum in the analysis chamber as well as the different parts of the system (detector, X-ray source, etc.)
- The operator of the system has the right to cancel any measurement if the sample is suspected to have risk on the safety of the operator or can cause damage to the instrument during the operation.